	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	948	wire adj bonding and (open or short) and (testing or test) and flip adj chip	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 13:49
2	BRS	L2	267	wire adj bonding and (open and short) and (testing or test) and flip adj chip	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 13:49
3	BRS	L3	296	wire adj (bonding or bonded) and (open and short) and (testing or test) and flip adj chip	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:02
4	BRS	L4	47270	wire-bonded or wire-bonding or (wire adj bond$6)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:03
5	BRS	L5	1245827	test or testing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:15

	Type	L #	Hits	Search Text	DBs	Time Stamp
6	BRS	L6	11148	open/short or (open near2 short)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:03
7	BRS	L7	730	5 near8 6	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:03
8	BRS	L8	34	7 and 4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:04
9	BRS	L9	3473541	test or testing or checked or checking or check or tested or examining or exam or determine or determing or determined or evaluate or evaluating or evaluated	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:17
10	BRS	L10	924	9 near4 6	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:17

	Type	L #	Hits	Search Text	DBs	Time Stamp
11	BRS	L11	10	10 same 4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:20
12	BRS	L12	38	10 and 4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:20
13	IS&R	L13	1	("6655023").PN.	USPAT	2004/03/10 14:28
14	IS&R	L14	1	("6433419").PN.	USPAT	2004/03/10 14:28
15	IS&R	L15	1	("6461896").PN.	USPAT	2004/03/10 14:28
16	BRS	L17	3	13 or 14 or 15	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:29
17	BRS	L19	7	4 with 6 with 9	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/10 14:32